

Notice of References Cited	Application/Control No. 10/775,163	Applicant(s)/Patent Under Reexamination KUDELKA, STEPHAN P.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,303,953	10-2001	Doan et al.	257/296
	C	US-6,365,485	04-2002	Shiao et al.	438/392
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	E	US-6,555,430	04-2003	Chudzik et al.	438/243
	F	US-6,781,180	08-2004	Martin et al.	257/301
	G	US-2002/0072171	06-2002	Forster et al.	438/243
	H	US-2003/0017675	01-2003	Chen et al.	438/380
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	K	US-5,407,534	04-1995	Thakur, Randhir P. S.	438/398
	L	US-5,587,870	12-1996	Anderson et al.	361/313
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	U	Microchip fabrication, 4th Edn., Peter Van Zant, pages 260, 269 and 270.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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